

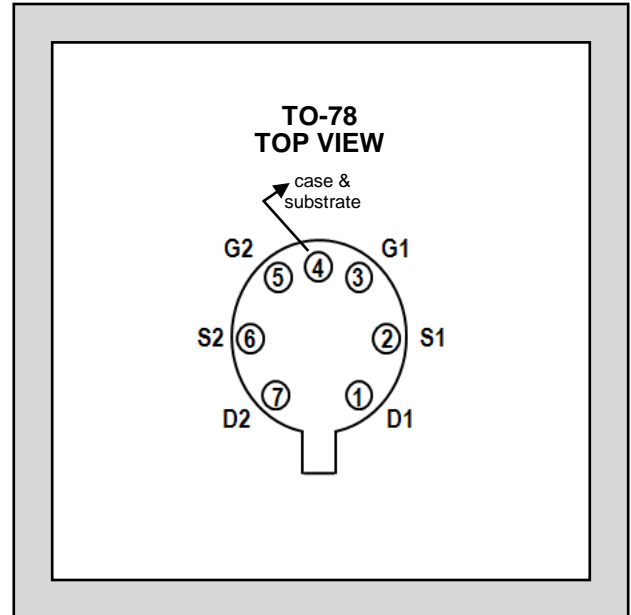
# LINEAR SYSTEMS

Improved Standard Products<sup>®</sup>

## 3N190 3N191

P-CHANNEL DUAL MOSFET  
ENHANCEMENT MODE

FEATURES	
DIRECT REPLACEMENT FOR INTERSIL 3N190 & 3N191	
LOW GATE LEAKAGE CURRENT	$I_{GSS} \leq \pm 10\text{pA}$
LOW TRANSFER CAPACITANCE	$C_{rss} \leq 1.0\text{pF}$
<b>ABSOLUTE MAXIMUM RATINGS<sup>1</sup></b>	
@ 25 °C (unless otherwise stated)	
<b>Maximum Temperatures</b>	
Storage Temperature	-65 to +150 °C
Operating Junction Temperature	-55 to +135 °C
<b>Maximum Power Dissipation @ TA=25°C</b>	
Continuous Power Dissipation One Side	300mW
Continuous Power Dissipation Both Sides	525mW
<b>Maximum Current</b>	
Drain to Source <sup>2</sup>	50mA
<b>Maximum Voltages</b>	
Drain to Gate <sup>2</sup>	30V
Drain to Source <sup>2</sup>	30V
Gate to Gate	±80V



### MATCHING CHARACTERISTICS @ 25 °C (unless otherwise stated) (V<sub>BS</sub> = 0V unless otherwise stated)

SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	CONDITIONS
$g_{fs1}/g_{fs2}$	Forward Transconductance Ratio	0.85		1.0		$V_{DS} = -15\text{V}$ , $I_D = -500\mu\text{A}$ , $f = 1\text{kHz}$
$V_{GS1-2}$	Gate to Source Threshold Voltage Differential			100	mV	$V_{DS} = -15\text{V}$ , $I_D = -500\mu\text{A}$
$\frac{\Delta V_{GS1-2}}{\Delta T}$	Gate to Source Threshold Voltage Differential with Temperature <sup>4</sup>			100	$\mu\text{V}/^\circ\text{C}$	$V_{DS} = -15\text{V}$ , $I_D = -500\mu\text{A}$ $T_S = -55$ to $+25$ °C
$\frac{\Delta V_{GS1-2}}{\Delta T}$	Gate to Source Threshold Voltage Differential with Temperature <sup>4</sup>			100		$V_{DS} = -15\text{V}$ , $I_D = -500\mu\text{A}$ $T_S = +25$ to $+125$ °C

### ELECTRICAL CHARACTERISTICS @ 25 °C (unless otherwise stated) (V<sub>SB</sub> = 0V unless otherwise stated)

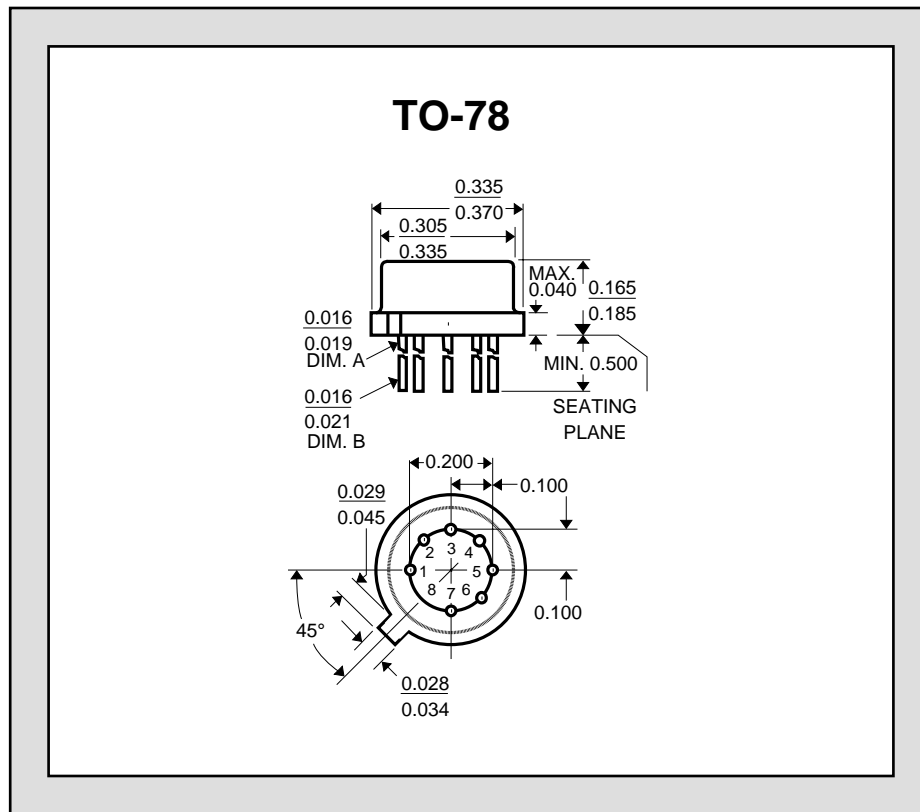
SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	CONDITIONS
$BV_{DSS}$	Drain to Source Breakdown Voltage	-40			V	$I_D = -10\mu\text{A}$
$BV_{SDS}$	Source to Drain Breakdown Voltage	-40				$I_S = -10\mu\text{A}$ , $V_{BD} = 0\text{V}$
$V_{GS}$	Gate to Source Voltage	-3.0		-6.5		$V_{DS} = -15\text{V}$ , $I_D = -500\mu\text{A}$
$V_{GS(th)}$	Gate to Source Threshold Voltage	-2.0		-5.0		$V_{DS} = V_{GS}$ , $I_D = -10\mu\text{A}$
$I_{GSSR}$	Reverse Gate Leakage Current			10	pA	$V_{GS} = 40\text{V}$
$I_{GSSF}$	Forward Gate Leakage Current			-10		$V_{GS} = -40\text{V}$
$I_{DSS}$	Drain Leakage Current "Off"			-200		$V_{DS} = -15\text{V}$
$I_{SDS}$	Source to Drain Leakage Current "Off"			-400		$V_{SD} = -15\text{V}$ , $V_{DB} = 0\text{V}$
$I_{D(on)}$	Drain Current "On" <sup>3</sup>	-5.0		-30.0	mA	$V_{DS} = -15\text{V}$ , $V_{GS} = -10\text{V}$
$I_{G1G2}$	Gate to Gate Isolation Current	-		±1.0	$\mu\text{A}$	$V_{G1G2} = \pm 80\text{V}$ , $I_D = I_S = 0 = \text{mA}$

**ELECTRICAL CHARACTERISTICS CONT. @ 25 °C (unless otherwise stated) ( $V_{SB} = 0V$  unless otherwise stated)**

SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	CONDITIONS
$g_{fs}$	Forward Transconductance <sup>4</sup>	1500		4000	μS	$V_{DS} = -15V, I_D = -5mA, f = 1kHz$
$g_{os}$	Output Admittance			300		
$r_{ds(on)}$	Drain to Source "On" Resistance			300	Ω	$V_{DS} = -20V, I_D = -100\mu A$
$C_{rss}$	Reverse Transfer Capacitance			1.0	pF	$V_{DS} = -15V, I_D = -5mA, f = 1MHz$
$C_{iss}$	Input Capacitance Output Shorted			4.5		
$C_{oss}$	Output Capacitance Input Shorted			3.0		

**SWITCHING CHARACTERISTICS**

SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	CONDITIONS
$t_{d(on)}$	Turn On Delay Time			15	ns	$V_{DD} = -15V, I_{D(on)} = -5mA, R_G = R_L = 1.4k\Omega$
$t_r$	Turn On Rise Time			30		
$t_{off}$	Turn Off Time			50		



**NOTES**

1. Absolute maximum ratings are limiting values above which serviceability may be impaired.
2. Per transistor.
3. Pulse:  $t = 300\mu s$ , Duty Cycle  $\leq 3\%$
4. Measured at end points,  $T_A$  and  $T_B$ .

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